

P54/74FCT651/A/C (P54/74PCT651/A/C) P54/74FCT652/A/C (P54/74PCT652/A/C) OCTAL TRANSCEIVER/REGISTER

★ FEATURES

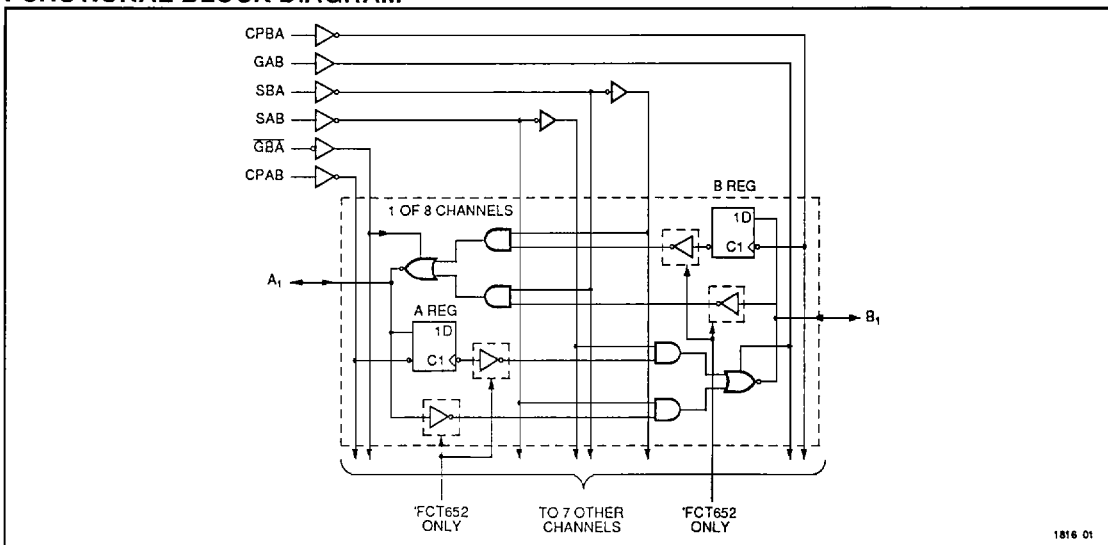
- Function, Pinout, and Drive Compatible with the FCT and F Logic
- FCT-C speed at 5.4ns max. (Com'I)
FCT-A speed at 6.3ns max. (Com'I)
- CMOS V_{OH} Levels for Low Power Consumption — Typically 1/3 of FAST Bipolar Logic
- Edge-rate Control Circuitry for Significantly Improved Noise Characteristics
- ESD protection exceeds 2000V
- Inputs and Outputs Interface Directly with TTL, NMOS, and CMOS Devices
- Outputs Meet Levels Required for CMOS Static RAM Low Power Standby Mode
- 64 mA Sink Current (Com'I), 48 mA (MII)
15 mA Source Current (Com'I), 12 mA (MII)
- Independent Register for A and B Buses
- Choice of Non-Inverting and Inverting Data Paths
- Multiplexed Real-Time and Stored Data
- 3-State Output
- Bidirectional Bus Transceiver and Registers
- Manufactured in 0.8 micron PACE Technology™

★ DESCRIPTION

The 'FCT651 and 'FCT652 consist of bus transceiver circuits, D-type flip-flops and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal storage registers. \overline{GAB} and \overline{GBA} control pins are provided to control the transceiver functions. \overline{SAB} and \overline{SBA} control pins are provided to select either real-time or stored data transfer. The circuitry used for select control will eliminate the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A low input level selects real-time data and a high selects stored data.

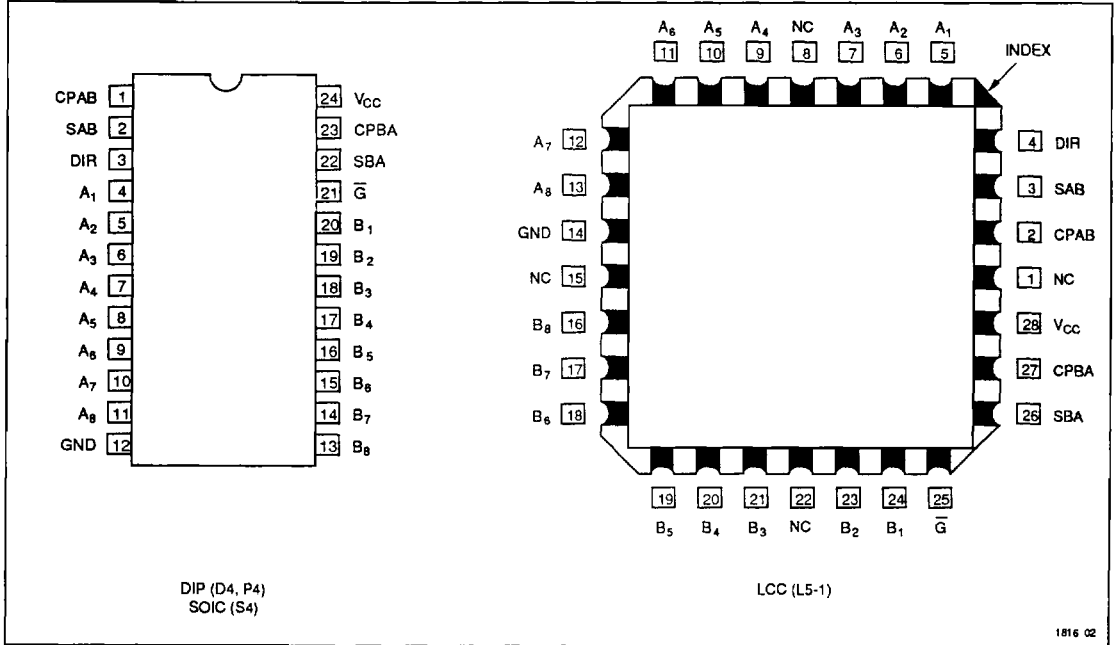
Data on the A or B data bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock pins (CPAB or CPBA), regardless of the select or enable control pins. When \overline{SAB} and \overline{SBA} are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling \overline{GAB} and \overline{GBA} . In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines will remain at its last state.

★ FUNCTIONAL BLOCK DIAGRAM



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PIN CONFIGURATIONS



FUNCTION TABLES

Inputs						Data I/O		Operation or Function	
GAB	GBA	CPAB	CPBA	SAB	SBA	A ₁ thru A ₈	B ₁ thru B ₈	'FCT651	'FCT652
L	H	H or L	H or L	X	X	Input	Input	Isolation Store A and B Data	Isolation Store A and B Data
L	H	\downarrow	\downarrow	X	X	Input	Input	Store A, Hold B Store A in both registers	Store A, Hold B Store A in both registers
X	H	\downarrow	H or L	X ²	X	Input	Unspecified ¹ Output	Store A, Hold B Store A in both registers	Store A, Hold B Store A in both registers
L	X	H or L	\downarrow	X	X	Unspecified ¹ Output	Input	Hold A, Store B Store B in both registers	Hold A, Store B Store B in both registers
L	L	X	X	X	L	Output	Input	Real-Time \bar{B} Data to A Bus	Real-Time B Data to A Bus
L	L	X	H or L	X	H	Output	Input	Stored B Data to A Bus	Stored B Data to A Bus
H	H	X	X	L	X	Input	Output	Real-Time \bar{A} Data to B Bus	Real-Time A Data to B Bus
H	H	H or L	X	H	X	Input	Output	Stored A Data to B Bus	Stored A Data to B Bus
H	L	H or L	H or L	H	H	Output	Output	Stored \bar{A} Data to B Bus and Stored B Data to A Bus	Stored A Data to B Bus and Stored B Data to A Bus

Notes:

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- The data output functions may be enabled or disabled by various signals at the GAB or \overline{GBA} inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.
- Select control = L: clocks can occur simultaneously.
Select control = H: clocks must be staggered in order to load both registers.
H = HIGH, L = LOW, X = Don't Care, \downarrow LOW-to-HIGH Transition

ABSOLUTE MAXIMUM RATINGS^{1,2}

Symbol	Parameter	Value	Unit
T _{STG}	Storage Temperature	-65 to +150	°C
T _A	Ambient Temperature Under Bias	-65 to +135	°C
V _{CC}	V _{CC} Potential to Ground	-0.5 to +7.0	V
I _{IN}	Input Current	-30 to +5.0	mA

Symbol	Parameter	Value	Unit
I _{OUTPUT}	Current Applied to Output	120	mA
V _{IN}	Input Voltage	-0.5 to V _{CC} + 0.5	V
V _{OUT}	Voltage Applied to Output	-0.5 to V _{CC} + 0.5	V

Notes:

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1. Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

2. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.

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RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

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Supply Voltage (V _{CC})	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

1816 Tbl 05

DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter	Min	Typ ¹	Max	Units	V _{CC}	Conditions	
V _{IH}	Input HIGH Voltage	2.0			V			
V _{IL}	Input LOW Voltage			0.8	V			
V _H	Hysteresis		0.35		V		All inputs	
V _{CD}	Input Clamp Diode Voltage		-0.7	-1.2	V	MIN	I _{IN} = -18mA	
V _{OH}	Output HIGH Voltage	V _{CC} = 3V, V _{IN} = 0.2V, or V _{CC} - 0.2V	V _{CC} - 0.2	V _{CC}		V		I _{OH} = -32µA
		Military/Commercial (CMOS)	V _{CC} - 0.2	V _{CC}		V	MIN	I _{OH} = -300µA
		Military (TTL)	2.4	4.3		V	MIN	I _{OH} = -12mA
		Commercial (TTL)	2.4	4.3		V	MIN	I _{OH} = -15mA
V _{OL}	Output LOW Voltage	V _{CC} = 3V, V _{IN} = 0.2V, or V _{CC} - 0.2V		GND	0.2	V		I _{OL} = 300µA
		Military/Commercial (CMOS)		GND	0.2	V	MIN	I _{OL} = 300µA
		Military (TTL)		0.3	0.55	V	MIN	I _{OL} = 48mA
		Commercial (TTL)		0.3	0.55	V	MIN	I _{OL} = 64mA
I _{IH}	Input HIGH Current (Except I/O Pins)			5	µA	MAX	V _{IN} = V _{CC}	
I _{IL}	Input LOW Current (Except I/O Pins)			-5	µA	MAX	V _{IN} = GND	
I _{IH}	Input HIGH Current ³ (Except I/O Pins)			5	µA	MAX	V _{IN} = 2.7V	
I _{IL}	Input LOW Current ³ (Except I/O Pins)			-5	µA	MAX	V _{IN} = 0.5V	
I _{IH}	Input HIGH Current (I/O Pins only)			15	µA	MAX	V _{IN} = V _{CC}	
I _{IL}	Input LOW Current (I/O Pins only)			-15	µA	MAX	V _{IN} = GND	
I _{IH}	Input HIGH Current ³ (I/O Pins only)			15	µA	MAX	V _{IN} = 2.7V	
I _{IL}	Input LOW Current ³ (I/O Pins only)			-15	µA	MAX	V _{IN} = 0.5V	
I _{OS}	Output Short Circuit Current ²	-60	-120		mA	MAX	V _{OUT} = 0.0V	
C _{IN}	Input Capacitance ³		5	10	pF		All inputs	
C _{OUT}	Output Capacitance ³		9	12	pF		All outputs	

Notes:

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1. Typical limits are at V_{CC} = 5.0V, T_A = +25°C ambient.
 2. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

3. This parameter is guaranteed but not tested.



DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ ¹	Max	Units	Conditions
I_{CC}	Quiescent Power Supply Current (CMOS inputs)	0.003	0.5	mA	$V_{CC} = \text{MAX}$, $f_1 = 0$, Outputs Open, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs)	0.5	2.0	mA	$V_{CC} = \text{MAX}$, $V_{IN} = 3.4V^2$, $f_1 = 0$, Outputs Open
I_{CCD}	Dynamic Power Supply Current ³	0.15	0.25	mA/ MHz	$V_{CC} = \text{MAX}$, One Input Toggling, 50% Duty Cycle, Outputs Open GAB = GND, GBA = GND, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
I_C	Total Power Supply Current ⁵	1.7	4.0	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, GAB = GND, GBA = GND, SAB = CPAB = GND, SBA = V_{CC} , $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		2.2	6.0	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, GAB = GND, GBA = GND, SAB = CPAB = GND, SBA = V_{CC} , $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$
		7.0	12.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 5\text{MHz}$, GAB = GBA = GND, SAB = CPAB = GND, SBA = V_{CC} , $V_{IN} = 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		9.2	21.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 5\text{MHz}$, GAB = GBA = GND, SAB = CPAB = GND, SBA = V_{CC} , $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$

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Notes:

- Typical values are at $V_{CC} = 5.0V$, +25°C ambient.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $$I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$$

$$I_C = I_{CC} + \Delta I_{CC} \cdot D_H \cdot N_T + I_{CCD} (f_0/2 + f_1 \cdot N_I)$$

$$I_{CC} = \text{Quiescent Current with CMOS input levels}$$

$$\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$$

- D_H = Duty Cycle for TTL inputs High
 - N_T = Number of TTL Inputs at D_H
 - I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
 - f_0 = Clock Frequency for Register Devices (Zero for Non-Register Devices)
 - f_1 = Input Frequency
 - N_I = Number of Inputs at f_1
- All currents are in milliamps and all frequencies are in megahertz.

